TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSV)

2SK2998

Chopper Regulator, DC-DC Converter Applications

Unit: mm

•	Low drain-source ON resistance	$: R_{DS}(ON) = 11.5 \Omega \text{ (typ.)}$
•	High forward transfer admittance	e : $ Y_{fs} = 0.4 \text{ S (typ.)}$
•	Low leakage current : IDSS	$= 100 \mu A \text{ (max) (VDS} = 500 \text{ V)}$

• Enhancement–mode $: I_{DSS} = 100 \, \mu A \, (max) \, (V_{DS} = 300 \, V)$ • $: V_{th} = 2.0 \sim 4.0 \, V \, (V_{DS} = 10 \, V, \, I_{D} = 1 \, mA)$

Maximum Ratings (Ta = 25°C)

Characteris	stics	Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	500	V	
Drain-gate voltage (Ro	_{SS} = 20 kΩ)	V_{DGR}	500	V	
Gate-source voltage		V_{GSS}	±30	V	
Drain current	DC (Note 1)	I _D	0.5	Α	
Diam current	Pulse (Note 1)	I _{DP}	1.5	Α	
Drain power dissipation		P_{D}	0.9	W	
Channel temperature		T _{ch}	150	°C	
Storage temperature ra	ange	T _{stg}	-55~150	°C	

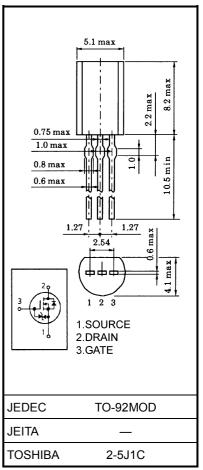
Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to ambient	R _{th (ch-a)}	138	°C/W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

This transistor is an electrostatic sensitive device.

Please handle with caution.



Weight: 0.36 g (typ.)

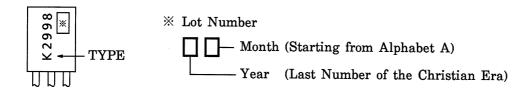
Electrical Characteristics (Ta = 25°C)

Charac	teristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I _{GSS}	V _{GS} = ±25 V, V _{DS} = 0 V	_	_	±10	μΑ
Gate-source breakdown voltage		V _(BR) GSS	I_D = ±10 mA, V_{GS} = 0 V	±30	_	_	V
Drain cut-off cur	rent	I _{DSS}	V _{DS} = 500 V, V _{GS} = 0 V	_	_	100	μΑ
Drain-source br	eakdown voltage	V _{(BR) DSS}	I _D = 10 mA, V _{GS} = 0 V	500	_	_	V
Gate threshold v	roltage	V_{th}	V _{DS} = 10 V, I _D = 1 mA	2.0	_	4.0	V
Drain-source OI	N resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 0.25 A	_	11.5	18	Ω
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 0.25 A	0.2	0.4	_	S
Input capacitanc	е	C _{iss}		_	75	_	
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	7	_	pF
Output capacitance		C _{oss}		_	25	_	
	Rise time	t _r	V_{GS} V_{OV} V_{OUT} V_{DD} V_{DD} V_{DD}	_	11	_	
Switching time	Turn-on time	t _{on}		_	18	_	ns
Switching time	Fall time	t _f		_	54	_	115
	Turn-off time	t _{off}	Duty $\leq 1\%$, $t_{\rm w} = 10 \mu \rm s$	_	95	_	
Total gate charge (gate-source plus gate-drain)		Qg		1	3.8	_	
Gate-source charge		Q _{gs}	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 0.5 \text{ A}$		1.9		nC
Gate-drain ("miller") Charge		Q _{gd}		_	1.9		

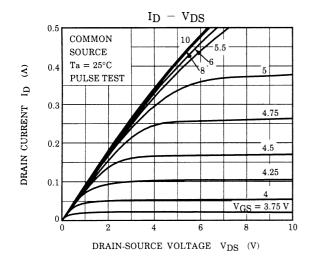
Source-Drain Ratings and Characteristics (Ta = 25°C)

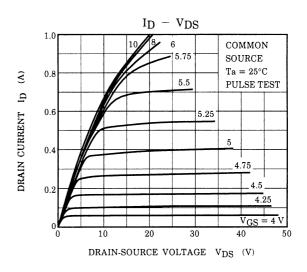
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	0.5	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	1.5	Α
Forward voltage (diode)	V _{DSF}	I _{DR} = 0.5 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 0.5 A, V _{GS} = 0 V dI _{DR} / dt = 100 A / μs	1	190	_	ns
Reverse recovery charge	Qrr	dI _{DR} / dt = 100 A / μs		380	_	nC

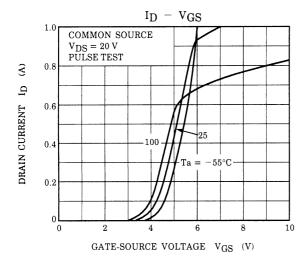
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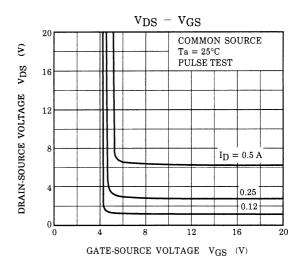


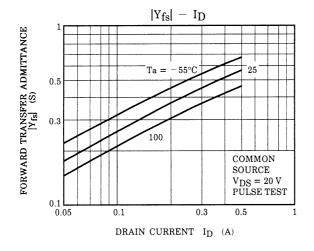
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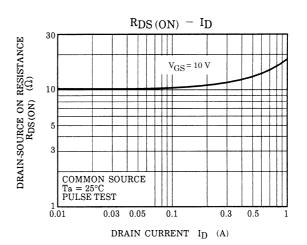




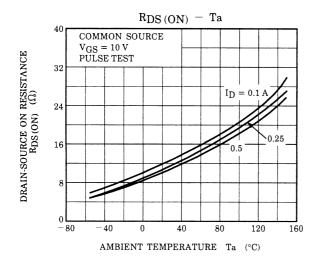


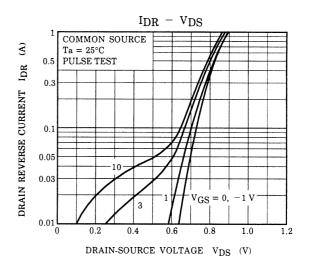


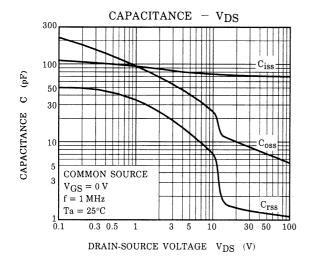


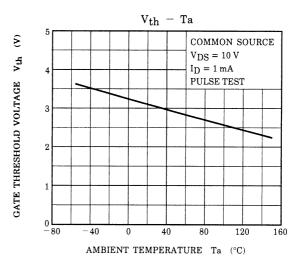


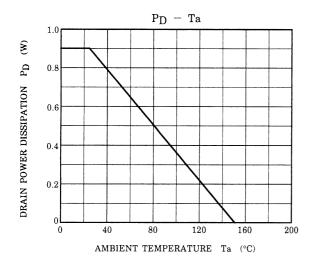
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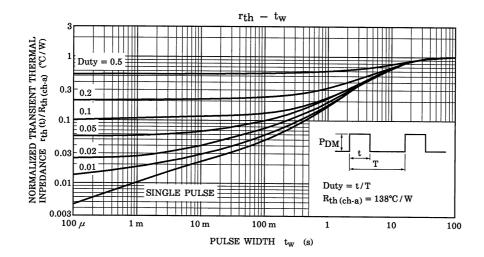


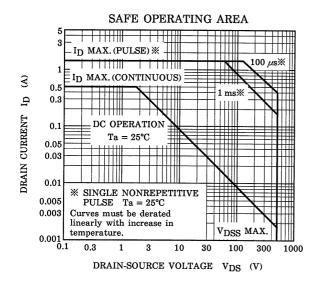






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